addenda and errata

A new version of the method for analysing peak broadening caused by local tilt distribution in double-crystal X-ray diffraction measurements. Erratum

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As a result of a printer's error, Fig. 9 of the paper by Nakashima [*J. Appl. Cryst.* (2000), **33**, 1376–1385] was incorrectly printed. The correct figure is given here.

References

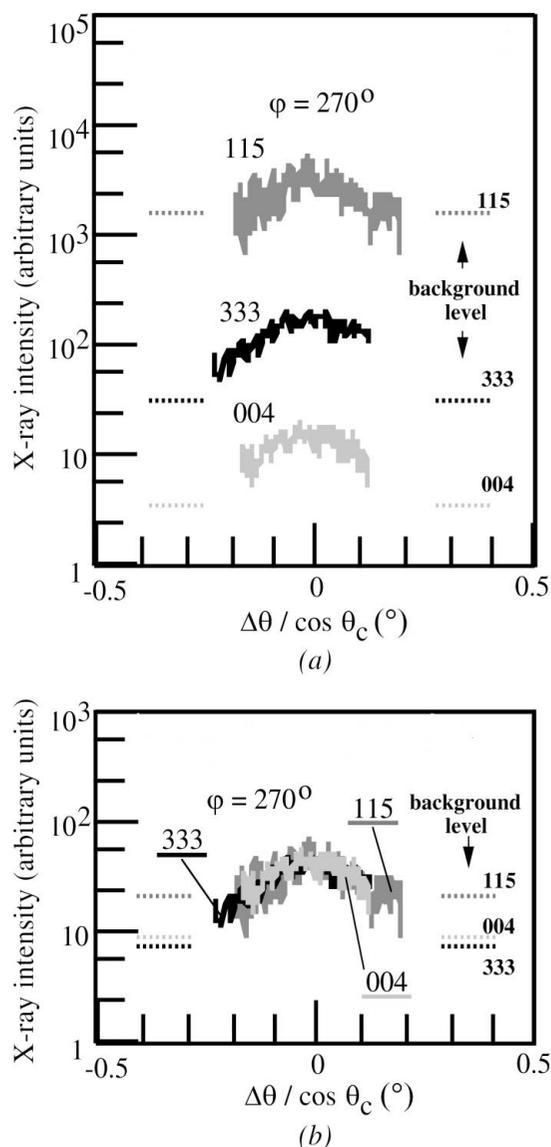Nakashima, K. (2000). *J. Appl. Cryst.* **33**, 1376–1385.

Figure 9
Result of the new analysis method when applied to the minus-first-order satellite peaks in the $\varphi = 270°$ profiles shown in Fig. 7. (a) Three different *hkl* profiles obtained after rescaling of the horizontal axis by $\cos\theta_c$. Each peak position is shifted to the origin. In other words, $\Delta\theta = \theta - \theta$(reference peak) and θ(minus-first-order satellite peak) is adopted as the θ(reference peak). (b) The three profiles in (a) replotted by adjusting their peak intensity tops to that of 004 in order to examine more accurately whether the three profiles are the same or not. The background level for each *hkl* profile is also indicated in (a) and (b). Only the signals above the background levels are significant for the comparison.